

**Search Notes**

Application/Control No.

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Examiner

Tan V. Mai

Applicant(s)/Patent under  
Reexamination

LIPP, JOHN

Art Unit

2193

**SEARCHED**

Class	Subclass	Date	Examiner
update	search	8/3/2005	MAI

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
update search (see search history printout(s) printout)	8/3/2005	MAI